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APPLICANT

Johr et al

FILING DATE

GROUP

2877

10/05/02
01/15/02

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
HP	AA	5872630	2/1999	Johr et al.	356	369	
A	AB	6034777	3/2000	Johr et al.	358	369	
	AC	4053232	10/1977	Dill et al.	356	118	
	AD	5596406	1/1997	Roencwaiss et al	356	327	
	AE	4668086	3/1987	Redner	356	367	
	AF	5757494	5/1998	Green et al	356	369	
	AG	5706212	1/1998	Thompson et al	364	525	
	AH	5582646	12/1996	Wooler et al.	118	208	
U	AI	5666201	9/1997	Johr et al	356	369	
	AJ	5521706	5/1996	Green et al	356	369	
HP	AK	5504582	4/1996	Johr et al	356	369	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL							
	AM							

None

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AR							
	AS							

None

EXAMINER

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
HP	AA	5329357	7/1994	Bernoux et al	356	369	
↑	AB	5764365	6/1998	Finarov	356	381	
	AC	5343293	8/1994	Berger et al	356	369	
	AD	4672196	6/1987	Canino	250	225	
	AE	4647207	3/1987	Bjork et al	357	369	
	AF	6081334	6/2000	Grumberger et al	356	357	
	AG	5410409	4/1995	Ray	356	369	
	AH	3874797	4/1975	Kasai	356	118	
	AI	5581350	12/1996	Chen et al	356	364	
U	AJ	5229833	7/1993	Stewart	356	364	
HP	AK	5706087	1/1998	Thompson et al	356	364	

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	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
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AM						

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
HA	AA	5 9 6 3 3 2 7	10/1994	He et al	356	369	
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL							
	AM			none				

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	AS			none

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MP
↑
An article by Johs, titled "Regression Calibration Method For Rotating Element Ellipsometers", which appeared in Thin Film Solids, Vol. 234 in 1993.

A paper by Nijs & Silfhout, titled "Systematic and Random Errors in Rotating-Analyzer Ellipsometry", J. Opt. Soc. Am. A., Vol. 5, No. 6, (June 1988).

An article by Jellison Jr. titled "Data Analysis for Spectroscopic Ellipsometry", Thin Film Solids, 234, (1993).

Papers of interest in the area by Azzam & Bashara;

"Unified Analysis of Ellipsometry Errors Due to Imperfect Components Cell-Window Birefringence, and Incorrect Azimuth Angles", J. of the Opt. Soc. Am., Vol 61, No. 5, (May 1971);

and

"Analysis of Systematic Errors in Rotating-Analyzer Ellipsometers", J. of the Opt. Soc. Am., Vol. 64, No. 11, (Nov. 1974).

A paper by Straaher et al., titled "The Influence of Cell Window Imperfections on the Calibration and Measured Data of Two Types of Rotating Analyzer Ellipsometers", Surface Sci., North Holland, 96, (1980).

An article by Collins titled "Automated Rotating Element Ellipsometers: Calibration, Operation, and Real-Time Applications", Rev. Sci. Instrum. 61(8), August 1990.

MP
An article by Kleim et al. titled "Systematic Errors in Rotating-Compensator Ellipsometry" published in J. Opt. Soc. Am./Vol. 11, No. 9, Sept 1994.